

# M-MOS Semiconductor Hong Kong Limited

# 20V N-Channel Enhancement-Mode MOSFET

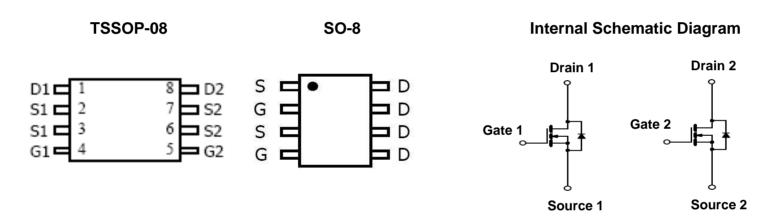
**V**<sub>DS</sub>= **20V** 

 $R_{DS(ON)}$ ,  $V_{gs}$ @2.5V,  $I_{ds}$ @5.2A = 40m $\Omega$ 

 $R_{DS(ON)}$ ,  $V_{gs}$ @4.5V,  $I_{ds}$ @6A = 30m  $\Omega$ 

#### **Features**

Advanced trench process technology High Density Cell Design For Ultra Low On-Resistance High Power and Current handing capability Ideal for Li ion battery pack applications



Top View N-Channel MOSFET

### Maximum Ratings and Thermal Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub> 20		V		
Gate-Source Voltage	V <sub>GS</sub>	± 12	V		
Continuous Drain Current		I <sub>D</sub>	6	- А	
Pulsed Drain Current 1)		I <sub>DM</sub>	20		
Maximum Power Dissipation	TA = 25°C	D	2	W	
	TA = 75°C	- P <sub>D</sub>	1.28		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C	
Junction-to-Ambient Thermal Resistance (PCB mounted) 2)		$R_{ heta JA}$	62.5	°C/W	

Note: 1. Repetitive Rating: Pulse width limited by the maximum junction temperature

V 1.4

<sup>2. 1-</sup>in<sup>2</sup> 2oz Cu PCB board



**Data Sheet** 

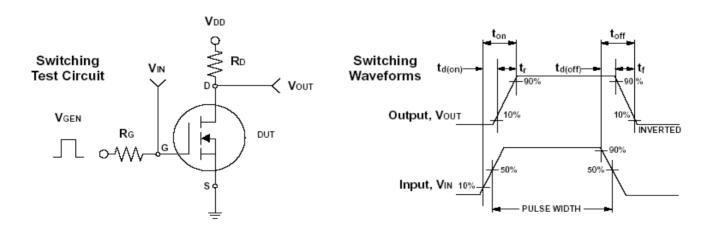
#### **N-Channel Enhancement-Mode MOSFET**

#### **ELECTRICAL CHARACTERISTICS**

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Static						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	$V_{GS} = 0V, I_{D} = 250uA$	20			V
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 2.5V, I_D = 5.2A$		32.0	40.0	mΩ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 4.5V, I_{D} = 6A$		23.0	30.0	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 250uA$	0.6	0.8	1.2	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 20V, V_{GS} = 0V$			1	uA
Gate Body Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
Dynamic <sup>3)</sup>						
Total Gate Charge	$Q_g$	$V_{DS} = 10V, I_{D} = 6A$ $V_{GS} = 4.5V$		4.86		nC
Gate-Source Charge	$Q_{gs}$			1.06		
Gate-Drain Charge	$Q_{gd}$			1.33		
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 10V, R_G = 6\Omega$ $I_D = 1A, V_{GS} = 4.5V$		12.64		ns
Turn-On Rise Time	t <sub>r</sub>			5		
Turn-Off Delay Time	t <sub>d(off)</sub>			24.84		
Turn-Off Fall Time	t <sub>f</sub>			4.88		
Input Capacitance	C <sub>iss</sub>	$V_{DS} = 8V, V_{GS} = 0V$ f = 1.0 MHz		547.12		pF
Output Capacitance	C <sub>oss</sub>			120.89		
Reverse Transfer Capacitance	C <sub>rss</sub>			87.47		
Source-Drain Diode						
Max. Diode Forward Current	Is				1.7	А
Diode Forward Voltage	V <sub>SD</sub>	$I_{S} = 1.7A, V_{GS} = 0V$			1.2	V

**Note**: Pulse test: pulse width <= 300us, duty cycle<= 2%

<sup>3.</sup> Guaranteed by design; not subject to production testing



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# **Notice**

- 1. Specification of the products displayed herein are subject to change without notice. Continuous development may necessitate changes in technical data without notice. M-MOS Semiconductor Sdn. Bhd. or anyone on its behalf, assumes no responsibility or liability for any errors or inaccuracies.
- 2. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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